

Search Notes

Application/Control No.

10/653,327

Examiner

Anish Sikri

Applicant(s)/Patent under
Reexamination

CHEN, CHIH-WEI

Art Unit

2109

SEARCHED

Class	Subclass	Date	Examiner
709	223	5/7/2007	AS
709	225	5/7/2007	AS
707	10	5/7/2007	AS
707	8	5/7/2007	AS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	5/7/2007	AS
Inventor name and Assignee search in PALM ExPO and EAST	5/7/2007	AS
Consulted with Rafael Perez-Gutierrez and George Bugg	5/7/2007	AS
"709"/\$.ccls. and (((one or single) adj writer) near4 ((several or multiple or many or few) adj readers))	5/7/2007	AS
((prohibit\$3 or prevent\$3 or inhibit\$3 or deny\$3) with ((multipl\$3 or group or several or many) same (login or access))) and	5/7/2007	AS